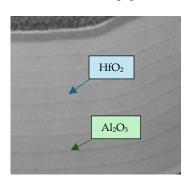
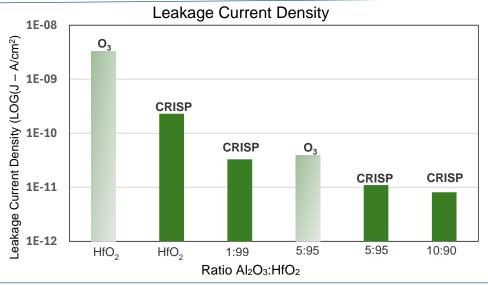
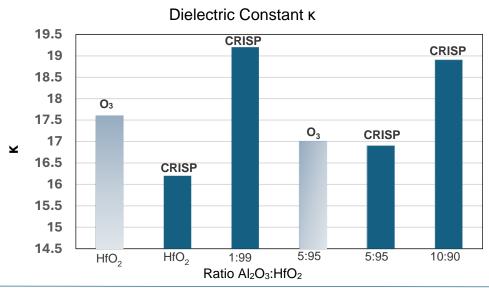
## **Supplemental Page**



**Figure 1:** Cross-sectional SEM image of HfAlO<sub>x</sub> nanolaminate showing HfO<sub>2</sub> layers (thick layer, blue label) and Al<sub>2</sub>O<sub>3</sub> layers (thin layer, green label)





**Figure 2**: Plots showing leakage current density (top) and dielectric constant (bottom) for various AlHfO<sub>x</sub> nanolaminate compositions. The first two data points are HfO<sub>2</sub> monoliths. For both data sets the lighter coloration indicates HfO<sub>2</sub> grown with an ozone process, while the darker color indicates HfO<sub>2</sub> grown with the CRISP process. Optimized film performance entails decreasing leakage current density and increasing dielectric constant.